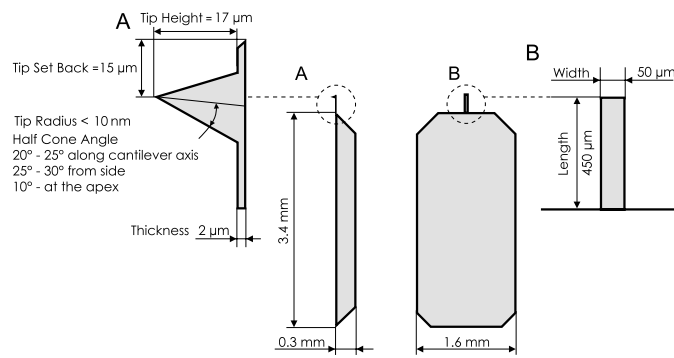




## AFM probe Model: **Contact**



- Contact Mode
- Rotated Monolithic Silicon Probe  
Symmetric Tip Shape  
Chipsize: 3.4 x 1.6 x 0.3 mm
- Coating: none
- This probe uses an “on scan angle” symmetric tip to provide a more symmetric representation of features over 200 nm.



	Typical Values	Range
Resonant Frequency	13 kHz	+/- 4 kHz
Force Constant	0.2 N/m	0.07 - 0.4 N/m
Cantilever Length	450 $\mu\text{m}$	+/- 10 $\mu\text{m}$
Mean Width	50 $\mu\text{m}$	+/- 5 $\mu\text{m}$
Thickness	2 $\mu\text{m}$	+/- 1 $\mu\text{m}$
Tip Height	17 $\mu\text{m}$	+/- 2 $\mu\text{m}$
Tip Set Back	15 $\mu\text{m}$	+/- 5 $\mu\text{m}$
Tip Radius	< 10 nm	
Coating	none	
Half Cone Angle	20° - 25° along cantilever axis 25° - 30° from side 10° at the apex	

Order Code	Units in Package	Coating	Price
Contact-10	10 pieces	none	\$200
Contact-50	50 pieces	none	\$850
Contact-W	380 pieces	none	\$3800